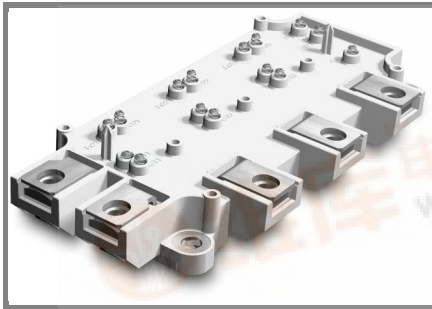


# SEMIX 151GD066HDS



SEMIX<sup>®</sup> 13s

## Trench IGBT Modules

### SEMIX 151GD066HDS

#### Target Data

#### Features

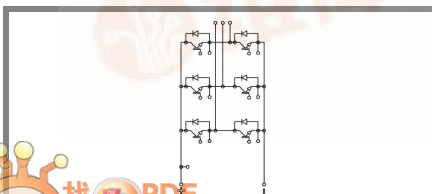
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient

#### Typical Applications

- Matrix Converter
- Resonant Inverter
- Current Source Inverter

#### Remarks

- Case temperatur limited to  $T_C=125^{\circ}C$  max.
- Product reliability results are valid for  $T_J=150^{\circ}C$
- SC data:  $t_p \leq 6 \mu s$ ;  $V_{GE} \leq 15 V$ ;  $T_J = 150^{\circ}C$ ;  $V_{CC} = 360 V$

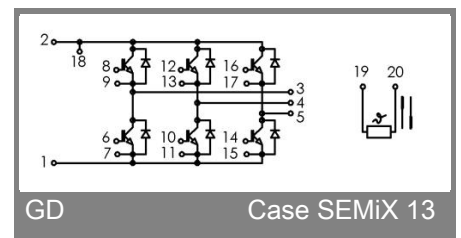
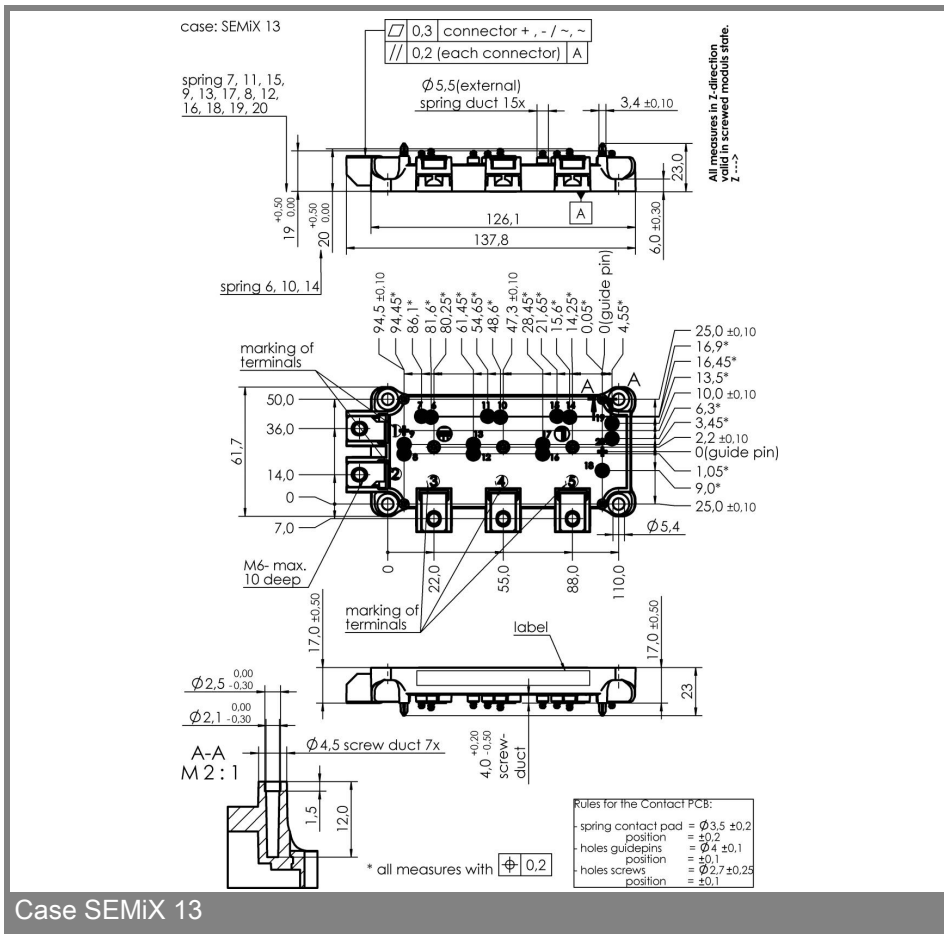


Absolute Maximum Ratings		$T_{case} = 25^{\circ}C$ , unless otherwise specified	
Symbol	Conditions	Values	Units
<b>IGBT</b>			
$V_{CES}$		600	V
$I_C$	$T_c = 25 (80)^{\circ}C, T_J = 150^{\circ}C$	180 (130)	A
$I_C$	$T_c = 25 (80)^{\circ}C, T_J = 175^{\circ}C$	200 (150)	A
$I_{CRM}$	$t_p = 1 ms$	300	A
$V_{GES}$		$\pm 20$	V
$T_J, (T_{stg})$		- 40 ... + 175 (125)	$^{\circ}C$
$V_{isol}$	AC, 1 min.	4000	V
<b>Inverse diode</b>			
$I_F$	$T_c = 25 (80)^{\circ}C, T_J = 150^{\circ}C$	150 (100)	A
$I_F$	$T_c = 25 (80)^{\circ}C, T_J = 175^{\circ}C$	170 (120)	A
$I_{FRM}$	$t_p = 1 ms$	300	A
$I_{FSM}$	$t_p = 10 ms; sin.; T_J = 25^{\circ}C$	980	A

Characteristics		$T_{case} = 25^{\circ}C$ , unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
<b>IGBT</b>					
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 4,8 mA$		5,8		V
$I_{CES}$	$V_{GE} = 0, V_{CE} = V_{CES}, T_J = 25 (^{\circ})^{\circ}C$			0,25	mA
$V_{CE(TO)}$	$T_J = 25 (150)^{\circ}C$		0,9 (0,85)	1 (0,9)	V
$r_{CE}$	$V_{GE} = 15 V, T_J = 25 (150)^{\circ}C$		3,7 (5,7)	6 (8)	m $\Omega$
$V_{CE(sat)}$	$I_{Cnom} = 150 A, V_{GE} = 15 V, T_J = 25 (150)^{\circ}C, chip level$		1,45 (1,7)	1,9 (2,1)	V
$C_{res}$	under following conditions				nF
$C_{oes}$	$V_{GE} = 0, V_{CE} = 25 V, f = 1 MHz$				nF
$C_{res}$					nF
$L_{CE}$					nH
$R_{CC'+EE'}$	terminal-chip, $T_c = 25 (125)^{\circ}C$		0,7 (1)		m $\Omega$
$t_{d(on)}/t_r$	$V_{CC} = 300 V, I_{Cnom} = 150 A$				ns
$t_{d(off)}/t_f$	$V_{GE} = \pm 15V$				ns
$E_{on} (E_{off})$	$R_{Gon} = R_{Goff} = 4 \Omega, T_J = 150^{\circ}C$		4 (6)		mJ
<b>Inverse diode</b>					
$V_F = V_{EC}$	$I_{Fnom} = 150 A; V_{GE} = 0 V; T_J = 25 (150)^{\circ}C, chip level$		1,4 (1,4)	1,6	V
$V_{(TO)}$	$T_J = 25 (150)^{\circ}C$		1 (0,85)	1,1	V
$r_T$	$T_J = 25 (150)^{\circ}C$		2,7 (3,7)	3,3	m $\Omega$
$I_{RRM}$	$I_{Fnom} = 150 A; T_J = 25 (150)^{\circ}C$				A
$Q_{rr}$	$di/dt = A/\mu s$				$\mu C$
$E_{rr}$	$V_{GE} = -15 V$				mJ
<b>Thermal characteristics</b>					
$R_{th(j-c)}$	per IGBT			0,3	K/W
$R_{th(j-c)D}$	per Inverse Diode			0,5	K/W
$R_{th(j-c)FD}$	per FWD				K/W
$R_{th(c-s)}$	per module		0,04		K/W
<b>Temperature sensor</b>					
$R_{25}$	$T_c = 25^{\circ}C$		5 $\pm$ 5%		k $\Omega$
$B_{25/85}$	$R_2 = R_1 \exp[B(1/T_2 - 1/T_1)]; T[K]; B$		3420		K
<b>Mechanical data</b>					
$M_s/M_t$	to heatsink (M5) / for terminals (M6)	3/2,5		5 /5	Nm
w			290		g



# SEMIX 151GD066HDs



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.